## **Test Fixtures**

LCZ Meters

Electrometers Switching Matrix

<b>Device Compat</b>	ibility	3323A	3327	8006	8007	8008	8009
Sheet Resistance							
Volume Resistance							
Axial Devices							
Chip Devices							
T0 18 Packages	4-Lead						
T0 5 Packages	4-Lead						
	8-Lead						
Dual In-Line Packages	≤24-Lead						
	≤28-Lead						
	≤48-Lead						
Prototyping Board							

	≤48-Lead						
Prototyping Board							
Instrument Compa	atibility	3323A	3327	8006	8007	8008	8009
Characterization Systems	4200-SCS						
DMMs	197A						
2000, 2001, 2002, 2010							
Nanovoltmeters	2182						
Sources	213						
	220						
	224			-			
	228A						
	230						
	263					_	
SMUs	236						
	237 238						
D'	428						
Picoammeters	428 485						
	486			-			
	487			-			
C-V Meters	590					-	
o i motoro	595						
Electrometers	6514					-	
	6517A						



3321

3322

3330

707A, 708A, 7072, 7172, 7174A



### 3323A Direct Test Fixture

del 3323A is designed for component ement by directly inserting the component fixture. It can accommodate axial-lead ents or radial-lead components without the component leads.

with: LCZ Meters.



Model 3327 Chip Component Test Fixture

The Model 3327 Chip Component Test Fixture provides a convenient method for testing the impedance of chip (i.e., SMD) components. The springloaded plunger provides consistent contact pressure for measuring low impedance devices and low predictable stray capacitance for measuring low capacitive devices.

For use with: LCZ Meters.

**Test fixtures** 

1.888.KEITHLEY (U.S. only)

www.keithley.com



## **Test Fixtures**



Model 8006 Component Test Fixture

The Model 8006 Component Test Fixture was designed specifically for making sensitive measurements on standard package devices with minimal setup time. Individual components may be connected to one of eight device sockets, including axial, 4, 8-, 10-, and 12-lead T0, and 28-pin DIPs. Instrumentation can be easily integrated through the 3-lug triax, BNC, or binding post connectors on the rear panel.

Signals from the test instruments are accessible at the test fixture's front panel. Mini jumper cables are provided to connect the signal to the appropriate device socket, which is also located on the front panel. This unique patch-board design allows for maximum versatility and the fastest possible setup times.

The 8006 Test Fixture maintains accuracy throughout the test circuit with greater than 100T $\Omega$  (1014 $\Omega$ ) path isolation, 4-wire connections, guarded jumpers, gold contacts and interconnects, and less than 100fA offset current. A hinged lid covers the component panel to provide a light-tight and shielded measurement.



### Model 8007 Semiconductor Test Fixture

The 8007 Semiconductor Test Fixture assures accurate measurement data for DC characterization of packaged devices. This test fixture provides a convenient means of making sensitive measurements



on Dual In-line Packages (DIPs) of 0.3 or 0.6 inch centers and up to 48 pins with the 24- or 48-pin socket. The prototyping board can be installed on the front panel for customized testing of packages

Accuracy is maintained to the DUT with isolation of more than  $1T\Omega$ . Offset current for the 8007 is less than 1pA, while maximum signal voltage is 200V with 1A peak current. A hinged cover provides light-tight and shielded measurements. 72 ferrite beads are also included for custom applications when DC tests are performed on active devices and some decoupling is required.

Supplied with interlock cable, phototyping

with twelve 3-slot triax plugs).

board, and two input cables (each terminated

with up to 72 pins.

Model 8008 Resistivity Chamber

The 8008 Resistivity Chamber is a guarded test fixture for measuring volume and surface resistivities. It assures good electrostatic shielding and high insulation resistance up to 1100V.

The 8008 accommodates sheet samples 64 to 102mm (2½ to 4 in) in diameter and up to 3.2mm (½ in) thick. It maintains good sample contact with uniform 1 pound pressure on smooth parallel samples. A lid switch activates the voltage disable input on the rear panel of the 487 or SMU.

The 8008 permits direct measurement of volume resistivity up to  $10^{18}\Omega$ -cm (on samples 0.1cm thick) and surface resistivity up to  $10^{17}\Omega$ /square in accordance with ASTM procedures.

#### Supplied with necessary cables to use with 487 or 236, 237 and 238.

**ENVIRONMENTAL LIMITS: Operating:** -25° to +85°C, 70% R.H. up to 35°C. **Storage:** -25° to +85°C.

**DIMENSIONS:** 108mm high × 165mm wide × 140mm deep (4<sup>1</sup>/<sub>4</sub> in × 6<sup>1</sup>/<sub>2</sub> in × 5<sup>1</sup>/<sub>2</sub> in).

WEIGHT: 1.45kg (3.19 lbs).



Model 8009 Resistivity Chamber

The Model 8009 is a guarded test fixture for measuring volume and surface resistivities. It assures good electrostatic shielding and high insulation resistance up to 1100V. The 8009 is designed for safe operation with the 6517A. Opening the lid of the 8009 automatically turns off the 6517A voltage source. The 8009 accommodates sheet samples from 64mm to 102mm (2½ to 4 in) in diameter and up to 3.2mm ( $\frac{1}{10}$  in) thick. It maintains good sample contact with uniform pressure (from 6 to 10 lbs depending on thickness) on smooth parallel samples.

With the front panel switch on the 8009, toggle between volume and surface resistivity, with the 6517A configured to calculate and display the appropriate result automatically. The 8009 permits direct measurement of volume resistivity up to  $10^{18}\Omega$ -cm (on samples 0.1cm thick) and surface resistivity up to  $10^{17}\Omega$ /square, in accordance with ASTM procedures.

# Supplied with necessary cables to use with 6517A, including Model 8607 Safety HV Dual Test Leads

**ENVIRONMENTAL LIMITS: Operating:** -30° to +85°C, 65% R.H. up to 35°C, derate 3% R.H./°C above 35°C. **Storage:** -25° to +85°C.

**DIMENSIONS:** 108mm high × 165mm wide × 140mm deep (4¼ in × 6½ in × 5½ in).

WEIGHT: 1.45kg (3.19 lbs).



